TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type (U-MOSIV)

# **TPCP8202**

#### Portable Equipment Applications

#### Motor Drive Applications

#### DC/DC Converters

· Lead (Pb)-free

• Low drain-source ON-resistance:  $R_{DS(ON)} = 19 \text{ m}\Omega$  (typ.)

High forward transfer admittance: |Y<sub>fs</sub>| = 20 S (typ.)

Low leakage current: I<sub>DSS</sub> = 10 μA (max)(V<sub>DS</sub> = 30 V)

Enhancement model: V<sub>th</sub> = 0.7 to 1.4V

 $(V_{DS} = 10 \text{ V}, I_D = 200 \mu\text{A})$ 

#### **Absolute Maximum Ratings (Ta = 25°C)**

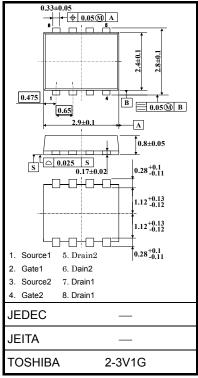
Cha	racteristic	Symbol	Rating	Unit	
Drain-source volta	ge	$V_{DSS}$	30	V	
Drain-gate voltage	(R <sub>GS</sub> = 20 kΩ)	$R_{GS} = 20 \text{ k}\Omega$ ) $V_{DGR}$ 30			
Gate-source voltage	je	V <sub>GSS</sub>	±12	V	
Drain current	DC (Note 1)	ID	5.5	Α	
Drain current	Pulse (Note 1)	I <sub>DP</sub>	22	A	
Drain power	Single-device operation (Note 3a)	P <sub>D (1)</sub>	1.48	W	
dissipation (t = 5 s) (Note 2a)	Single-device value at dual operation (Note 3b)	P <sub>D (2)</sub>	1.23		
Drain power	Single-device operation (Note 3a)	P <sub>D (1)</sub>	0.58		
dissipation (t = 5 s) (Note 2b)	Single-device value at dual operation (Note 3b)	P <sub>D (2)</sub>	0.36		
Single-pulse avala	nche energy (Note 4)	E <sub>AS</sub>	7.86	mJ	
Avalanche current		I <sub>AR</sub>	5.5	Α	
Repetitive avalanc Single-device value		E <sub>AR</sub>	AR 0.12		
Channel temperatu	ıre	T <sub>ch</sub>	150 °C		
Storage temperatu	emperature range		-55 to 150	°C	

Note: For Notes 1 to 6, see the next page.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

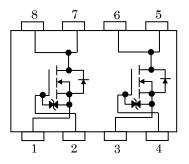
This transistor is an electrostatic-sensitive device. Handle with care.

Unit: mm

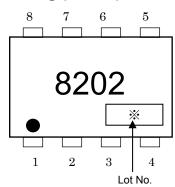


Weight: 0.017 g (typ.)

#### **Circuit Configuration**



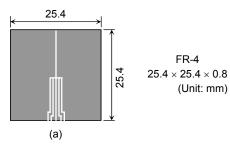
#### Marking (Note 6)

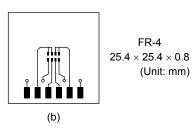


#### **Thermal Characteristics**

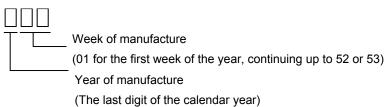
Characteristic		Symbol	Max	Unit	
Thermal resistance, channel to ambient (t = 5 s) (Note 2a)	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	84.5	- °C/W	
	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	101.6		
Thermal resistance, channel to ambient	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	215.5 °C/\		
(t = 5 s) (Note 2b)	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	347.2	C/VV	

- Note 1: Ensure that the channel temperature does not exceed 150°C.
- Note 2: (a) Device mounted on a glass-epoxy board (a)
- (b) Device mounted on a glass-epoxy board (b)





- Note 3: a) The power dissipation and thermal resistance values shown are for a single device. (During single-device operation, power is applied to one device only.)
  - b) The power dissipation and thermal resistance values shown are for a single device. (During dual operation, power is applied to both devices evenly.).
- Note 4:  $V_{DD} = 24$  V,  $T_{ch} = 25$ °C (initial), L = 0.2 mH,  $R_G = 25$   $\Omega$ ,  $I_{AR} = 5.5$  A
- Note 5: Repetitive rating: Pulse width limited by Max. Channel temperature.
- Note 6: on the lower left of the marking indicates Pin 1.
  - \* Weekly code (3 digits):



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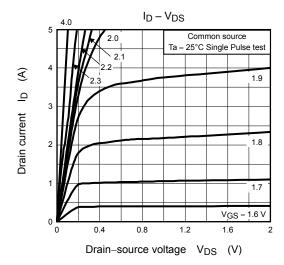
## Electrical Characteristics (Ta = $25^{\circ}$ C)

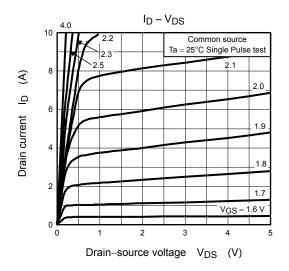
Ch	aracteristic	Symbol	Test Condition	Min	Тур.	Max	Unit	
Gate leakage cui	rrent	I <sub>GSS</sub>	$V_{GS} = \pm 10 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μА	
Drain cutoff curre	ent	I <sub>DSS</sub>	V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V	_	_	10	μА	
Drain-source bre	akdown voltage	V <sub>(BR)</sub> DSS	$I_D = 10$ mA, $V_{GS} = 0$ V	30	_	_	V	
Diain-source bre	akuowii voitage	V (BR) DSX	$I_D = 10 \text{ mA}, V_{GS} = -12 \text{ V}$	15	_	_	V	
Gate threshold ve	oltage	V <sub>th</sub>	$V_{DS} = 10 \text{ V}, I_D = 200 \mu\text{A}$	0.7	_	1.4	V	
		R <sub>DS</sub> (ON)	V <sub>GS</sub> = 2.5 V, I <sub>D</sub> = 2.8 A	_	29	39	mΩ	
Drain-source ON	-resistance	R <sub>DS</sub> (ON)	V <sub>GS</sub> = 4.0 V, I <sub>D</sub> = 2.8A	_	20	24		
		R <sub>DS</sub> (ON)	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 2.8A	_	19	23		
Forward transfer admittance		Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 2.8A	10	20	_	S	
Input capacitance		C <sub>iss</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	2150	_	pF	
Reverse transfer capacitance		C <sub>rss</sub>		_	155	_		
Output capacitance		Coss	]	_	165	_		
	Rise time	t <sub>r</sub>	V <sub>GS</sub> 10 V	_	10	_		
	Turn-on time	t <sub>on</sub>		_	20	_		
	Fall time	t <sub>f</sub>		_	19	_	ns	
	Turn-off time	t <sub>off</sub>	Duty ≦ 1%, t <sub>w</sub> = 10 μs	_	90	_		
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \simeq 24 \text{ V, V}_{GS} = 10 \text{ V,}$ $I_D = 5.5 \text{ A}$		28	_		
Gate-source charge1		Q <sub>gs1</sub>			4		nC	
Gate-drain ("Miller") charge		Q <sub>gd</sub>		_	8	_		

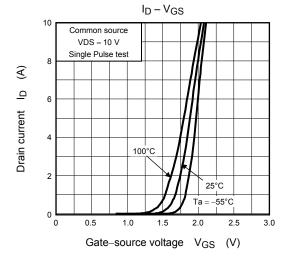
### Source-Drain Ratings and Characteristics (Ta = 25°C)

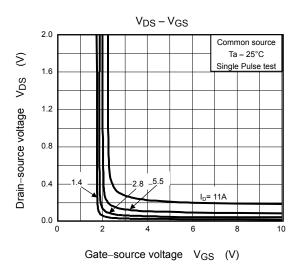
Characteristic		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I <sub>DRP</sub>	_	_	_	22	Α
Forward voltage (diode)		$V_{DSF}$	IDR = 5.5 A, $VGS = 0 V$	_	_	-1.2	V

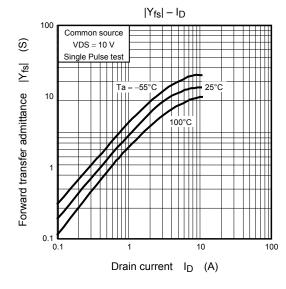
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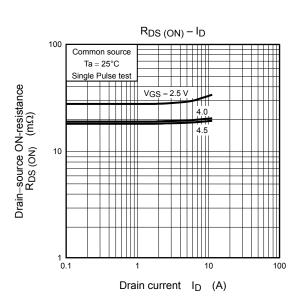


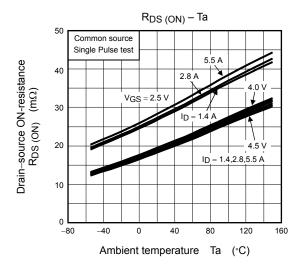


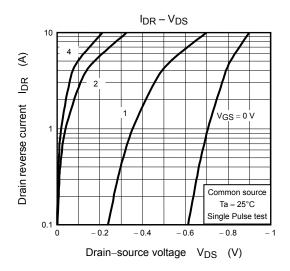


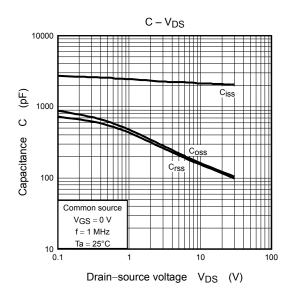


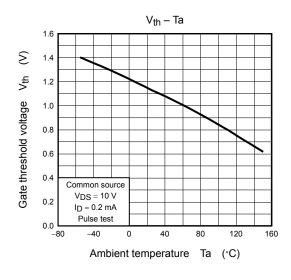


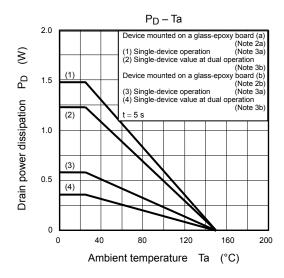


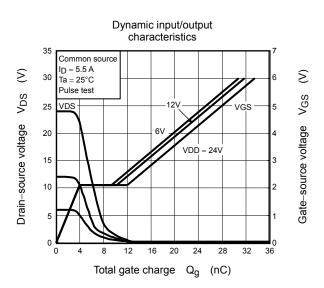




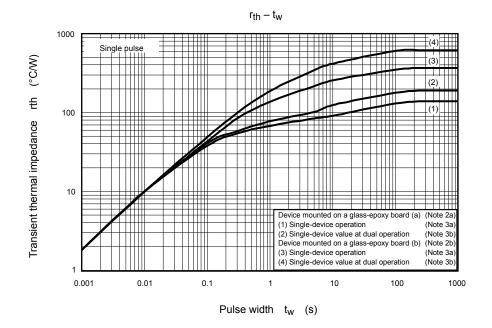


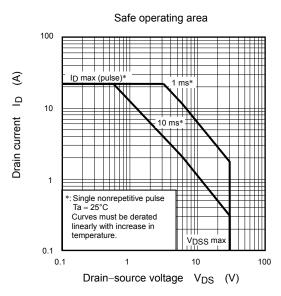






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